

<b>Notice of References Cited</b>	Application/Control No. 10/030,064	Applicant(s)/Patent Under Reexamination WEHL ET AL.	
	Examiner Blaise L Mouttet	Art Unit 2853	Page 1 of 1

IDC-US Ref -7

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5229016	07-1993	Hayes et al.	222/590
	B	US-5418561	05-1995	Fujioka	347/88
	C	US-5471232	11-1995	Hosono et al.	347/70
	D	US-5622897	04-1997	Hayes	438/21
	E	US-5779971	07-1998	Tsung Pan et al.	266/237
	F	US-5793294	08-1998	<del>Kato</del> Schepka	347/70
	G	US-6003968	12-1999	Kozawa	347/20
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.